

[54] MICROMETER

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[\*\*] Term: 14 Years

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[52] U.S. Cl. .... D10/73; D10/70

[58] Field of Search ..... D10/73, 74; 33/164 R, 33/164 B, 164 C, 164 D, 165, 166, 167, 147 E, 170

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[57] CLAIM

The ornamental design for a micrometer, as shown.

DESCRIPTION

FIG. 1 is a front and top-right perspective view of a micrometer showing my new design; FIG. 2 is a re-oriented perspective view of FIG. 1; FIG. 3 is a front elevational view thereof; FIG. 4 is a rear elevational view thereof; FIG. 5 is a top plan view thereof; FIG. 6 is a bottom plan view thereof; FIG. 7 is a left side elevational view thereof; and FIG. 8 is a right side elevational view thereof.

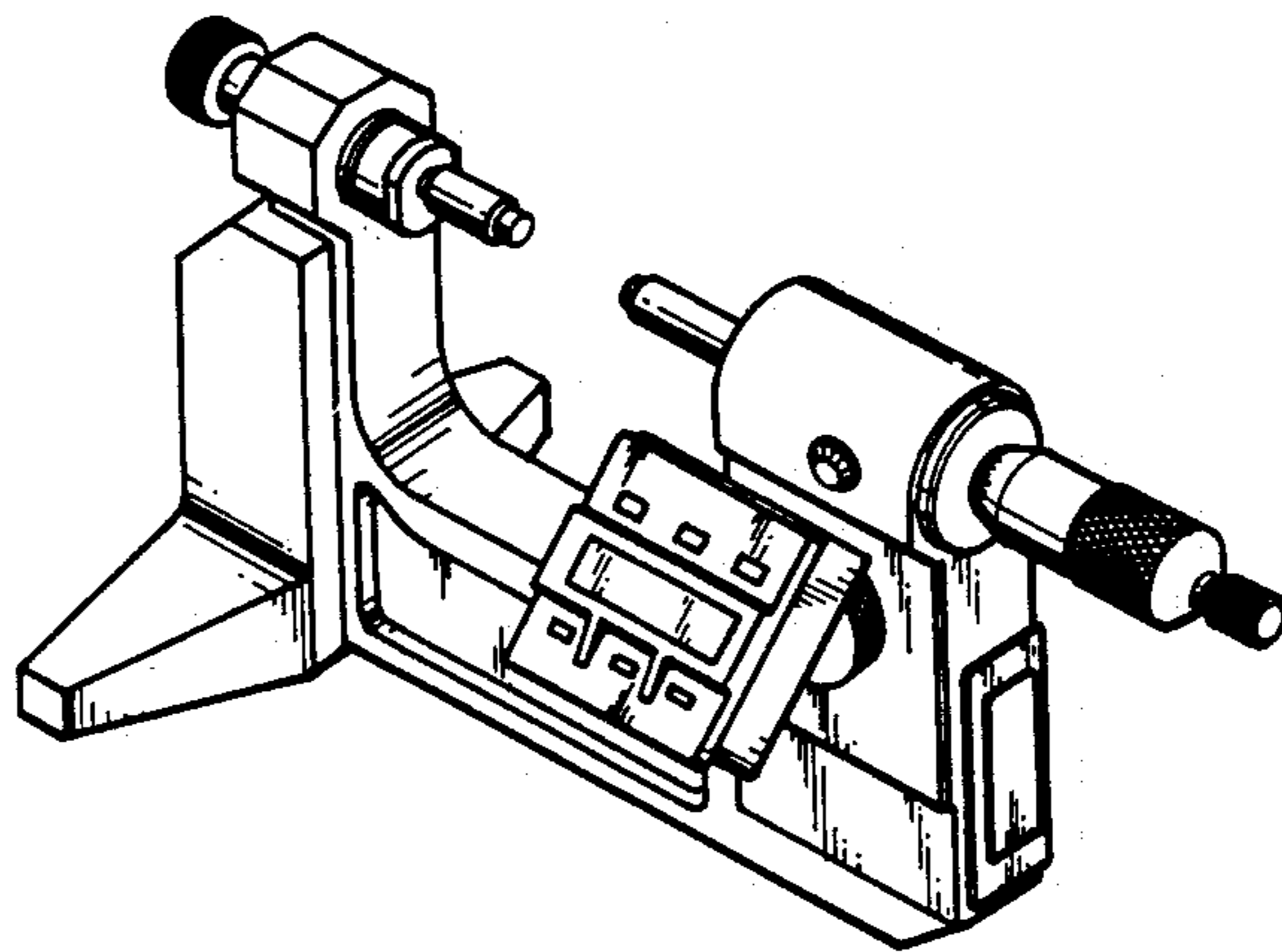


FIG. 1

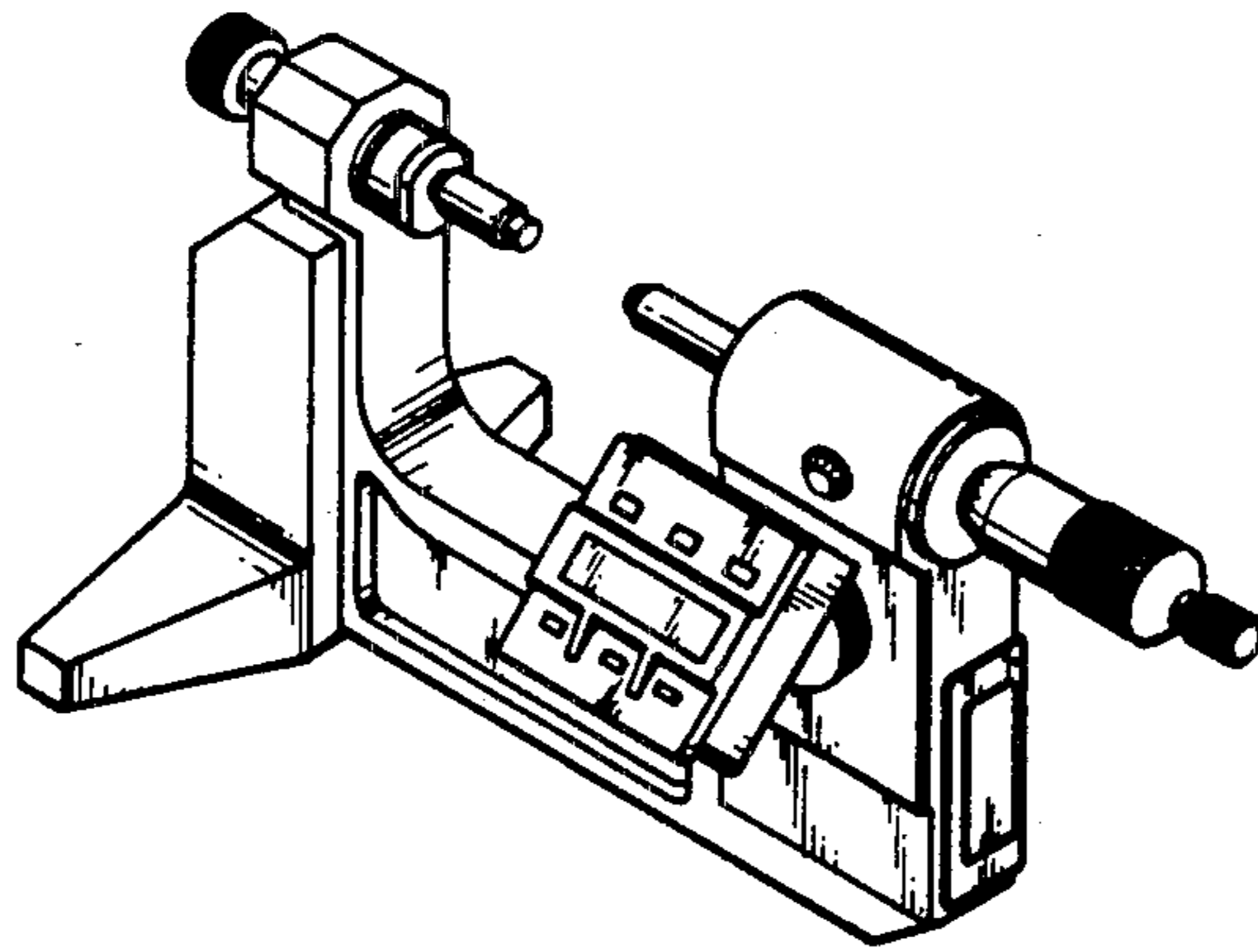


FIG. 2

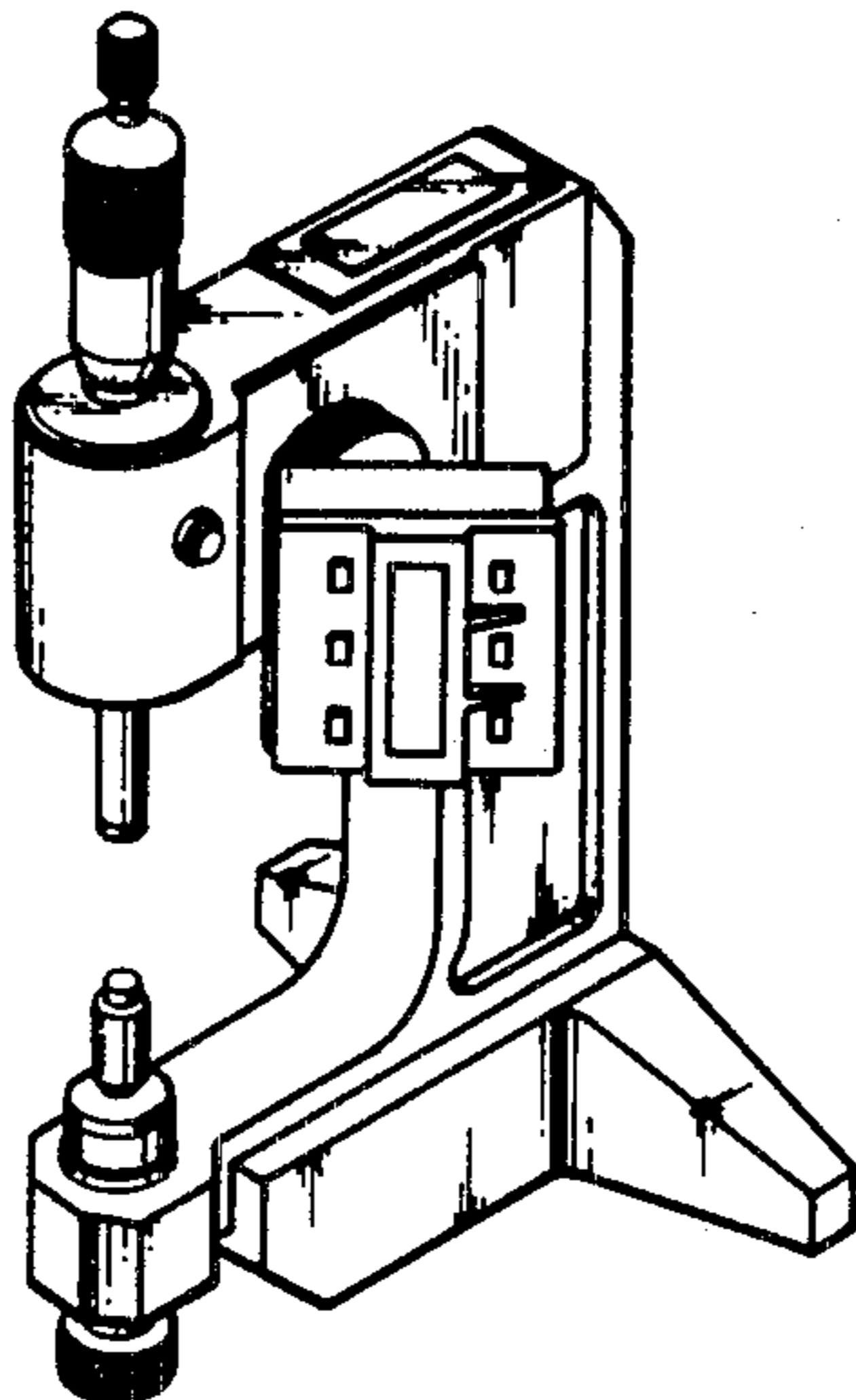


FIG. 3

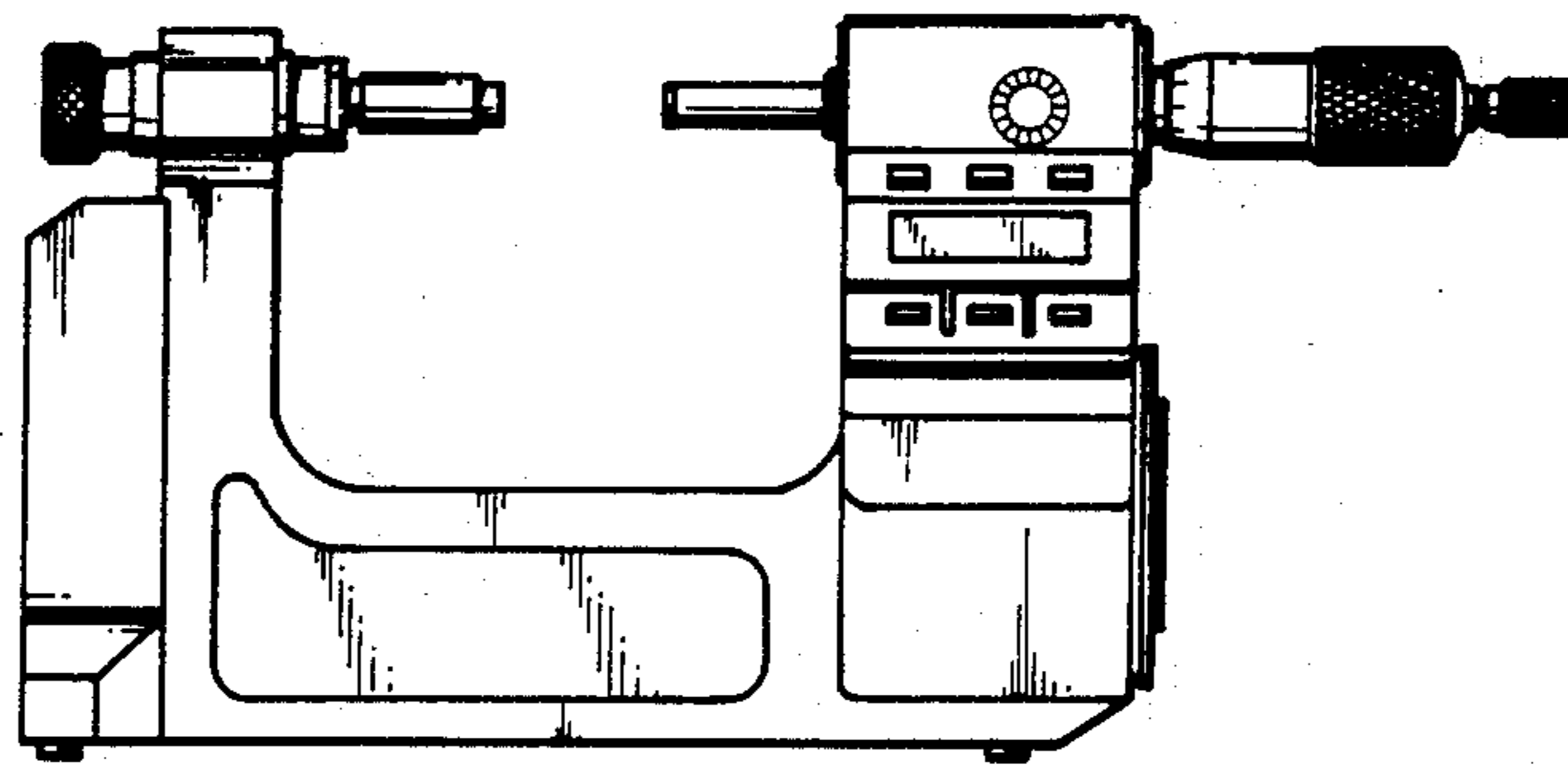


FIG. 4

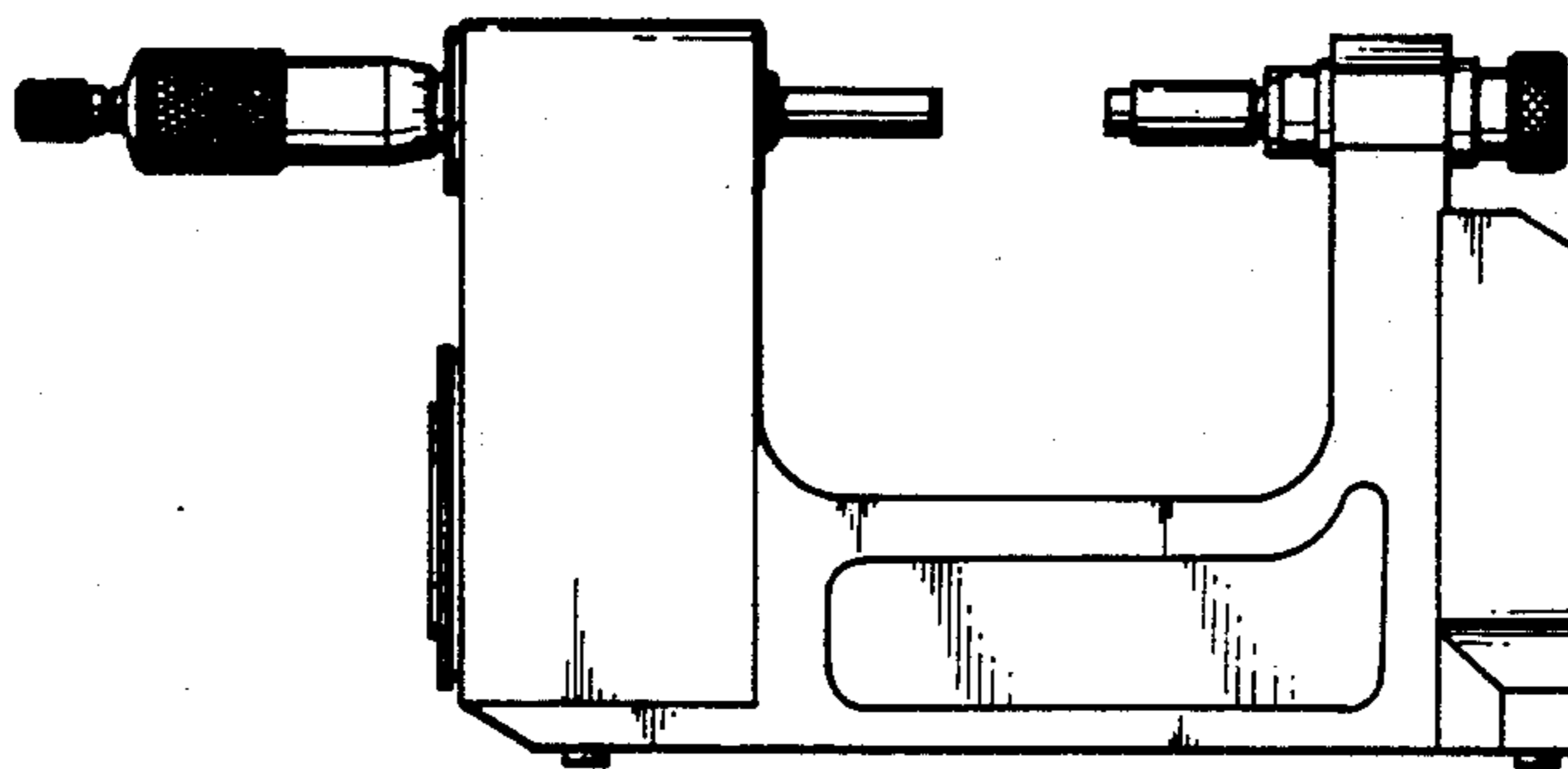


FIG. 5

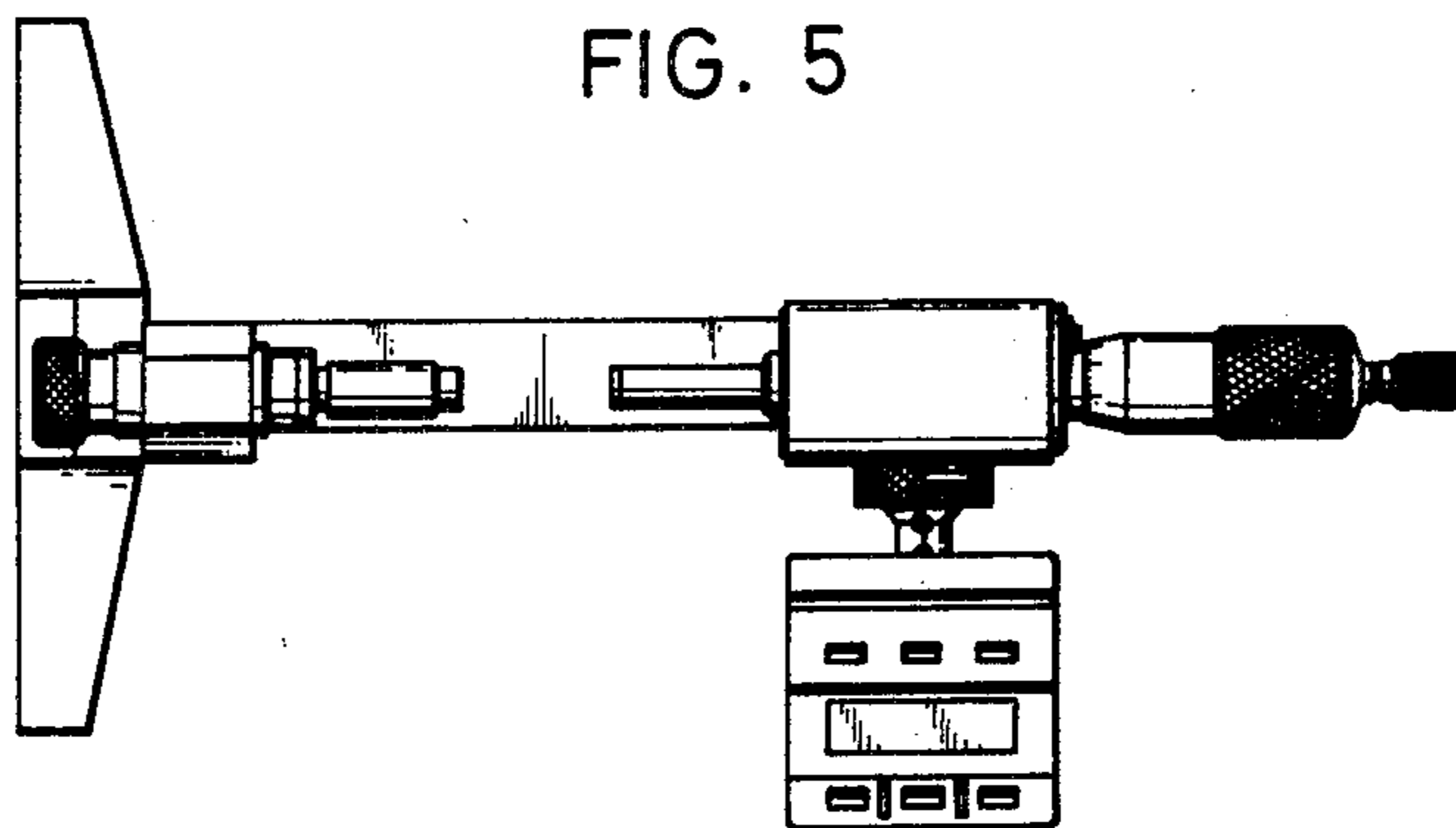


FIG. 6

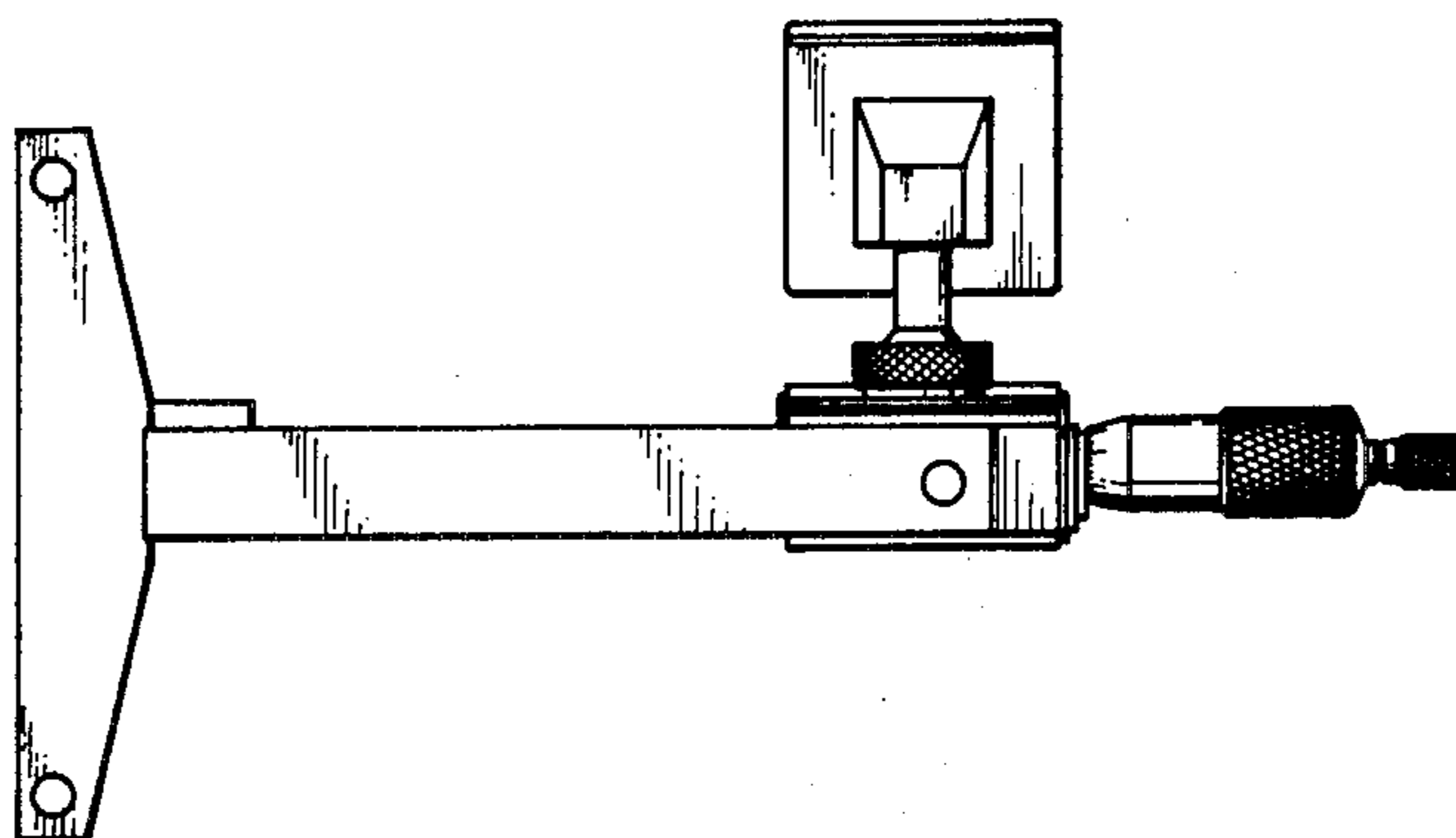


FIG. 7

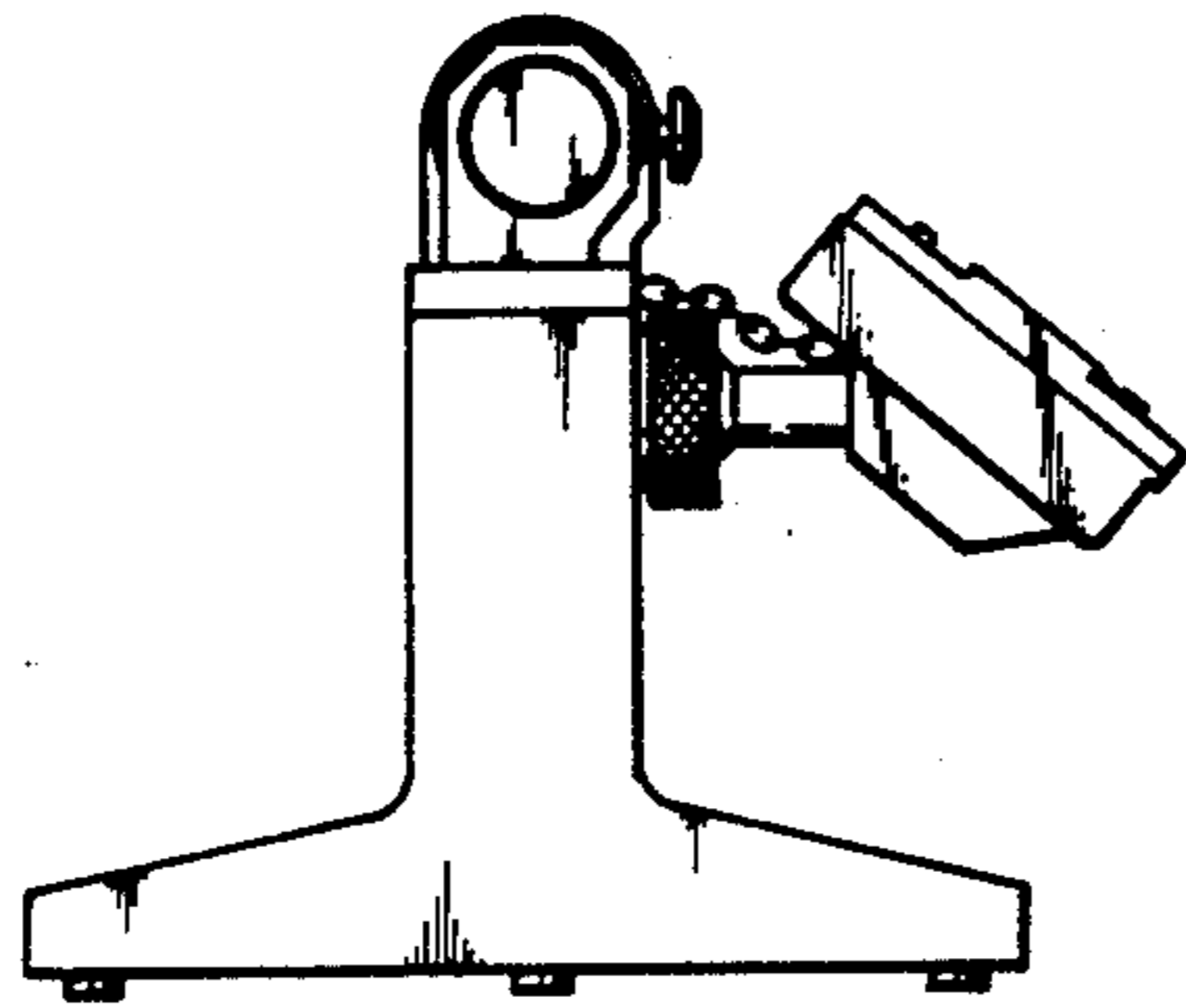


FIG. 8

